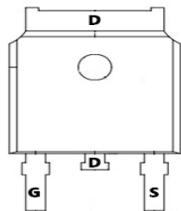
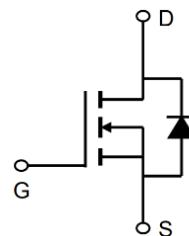
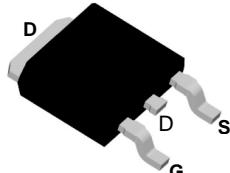


TMG50N10AD
N-Channel Enhancement Mosfet

General Description <ul style="list-style-type: none"> • Low R_{DS(ON)} • RoHS and Halogen-Free Compliant Applications <ul style="list-style-type: none"> • Load switch • PWM 	General Features <p> $V_{DS} = 100V$ $I_D = 48A$ $R_{DS(ON)} = 20\ m\Omega$(typ.) @ $V_{GS} = 10V$ </p> <p> 100% UIS Tested 100% R_g Tested </p> 
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D:TO-252-3L


Marking: G50N10

Absolute Maximum Ratings $T_c = 25^\circ C$ unless otherwise specified

Symbol	Parameter		Max.	Units
V_{DSS}	Drain-Source Voltage		100	V
V_{GSS}	Gate-Source Voltage		± 20	V
I_D	Continuous Drain Current ^{note5}	$T_c = 25^\circ C$	48	A
I_D	Continuous Drain Current ^{note5}	$T_c = 100^\circ C$	31	A
I_{DM}	Pulsed Drain Current ^{note3}		177	A
P_D	Power Dissipation ^{note2}	$T_c = 25^\circ C$	27	W
I_{AS}	Avalanche Current ^{note3,6}		8	A
E_{AS}	Single Pulse Avalanche Energy ^{note3,6}		16	mJ
R_{eJC}	Thermal Resistance, Junction to Case		4.65	$^\circ C/W$
R_{eJA}	Thermal Resistance, Junction to Ambient ^{note1,4}		62	$^\circ C/W$
T_J, T_{STG}	Operating and Storage Temperature Range		-55 to +150	$^\circ C$

TMG50N10AD
N-Channel Enhancement Mosfet
Electrical Characteristics $T_C=25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
Off Characteristic						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$	100	-	-	V
I_{DSS}	Drain-Source Leakage Current	$V_{DS} = 80\text{V}, V_{GS} = 0\text{V}$	-	-	1	μA
I_{GSS}	Gate to Body Leakage Current	$V_{DS} = 0\text{V}, V_{GS} = \pm 20\text{V}$	-	-	± 100	nA
On Characteristics						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1.2	1.8	2.6	V
$R_{DS(on)}$	Static Drain-Source On-Resistance	$V_{GS} = 10\text{V}, I_D = 15\text{A}$	-	20	23	$\text{m}\Omega$
		$V_{GS} = 4.5\text{V}, I_D = 10\text{A}$	-	23	26	$\text{m}\Omega$
I_{fs}	Forward Threshold Voltage	$V_{DS} = 10\text{V}, I_D = 20\text{A}$	-	22	-	S
R_g	Gate Resistance	$V_{DS} = V_{GS} = 0\text{V}, f = 1.0\text{MHz}$	-	1.62	-	Ω
Dynamic Characteristics						
C_{iss}	Input Capacitance	$V_{DS} = 50\text{V}, V_{GS} = 0\text{V}, f = 1.0\text{MHz}$	-	1822	-	pF
C_{oss}	Output Capacitance		-	310	-	pF
C_{rss}	Reverse Transfer Capacitance		-	23.5	-	pF
Switching Characteristics						
Q_g	Total Gate Charge	$V_{DS} = 50\text{V}, I_D = 20\text{A}, V_{GS} = 10\text{V}$	-	22.7	-	nC
Q_{gs}	Gate-Source Charge		-	6.2	-	
Q_{gd}	Gate-Drain("Miller") Charge		-	5.3	-	
$t_{d(on)}$	Turn-On Delay Time	$V_{DS} = 50\text{V}, I_D = 20\text{A}, R_G = 3\Omega, V_{GS} = 10\text{V}$	-	15	-	ns
t_r	Turn-On Rise Time		-	3.2	-	
$t_{d(off)}$	Turn-Off Delay Time		-	30	-	
t_f	Turn-Off Fall Time		-	7.6	-	
Diode Characteristics						
I_s	Continuous Source Current		-	-	48	A
V_{SD}	Diode Forward Voltage	$I_s = 20\text{A}, V_{GS} = 0\text{V}$	-	0.88	1.0	V
t_{rr}	Reverse Recovery Time	$I_{SD} = 20\text{A}, dI_{SD}/dt = 100\text{A}/\mu\text{s}$	-	45	-	ns
Q_{rr}	Reverse Recovery Charge		-	59	-	nC

Notes:

- The value of $R_{\theta JC}$ is measured in a still air environment with $TA = 25^\circ\text{C}$ and the maximum allowed junction temperature of 150°C . The value in any given application depends on the user's specific board design.
- The power dissipation P_D is based on $T_{J(MAX)} = 150^\circ\text{C}$, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.
- Single pulse width limited by junction temperature $T_{J(MAX)} = 150^\circ\text{C}$.
- The $R_{\theta JA}$ is the sum of the thermal impedance from junction to case $R_{\theta JC}$ and case to ambient.
- The maximum current rating is package limited.
- The EAS data shows Max. rating. The test condition is $V_{DS} = 50\text{V}, V_{GS} = 10\text{V}, L = 0.5\text{mH}$

Typical Performance Characteristics

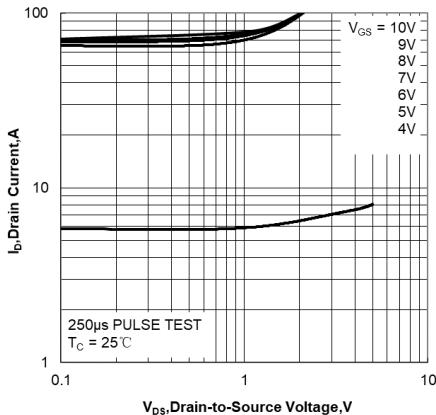


Figure 1. Output Characteristics

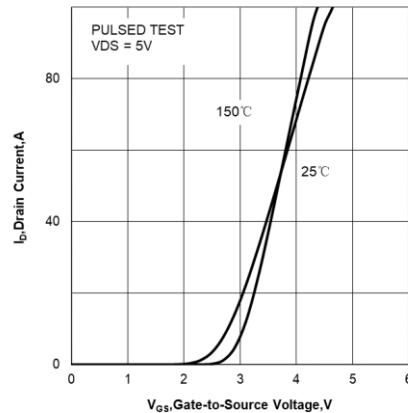
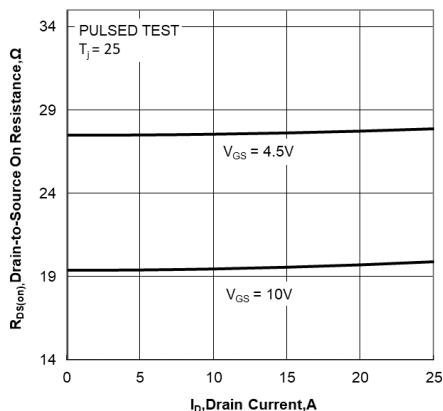
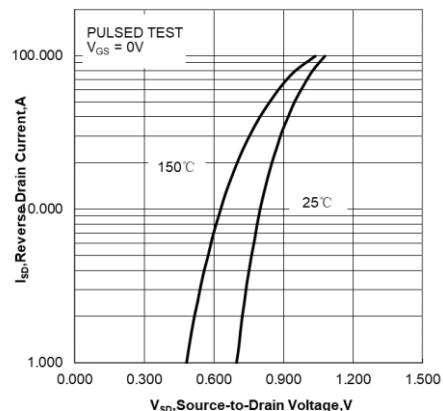


Figure 2. Transfer Characteristics



**Figure 3. Drain-to-Source On Resistance
vs Drain Current**



**Figure 4. Body Diode Forward Voltage
vs Source Current and Temperature**

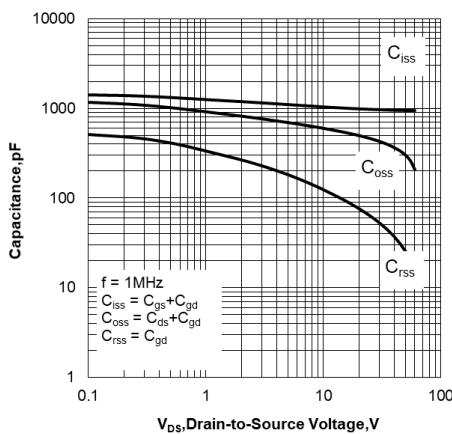


Figure 5. Capacitance Characteristics

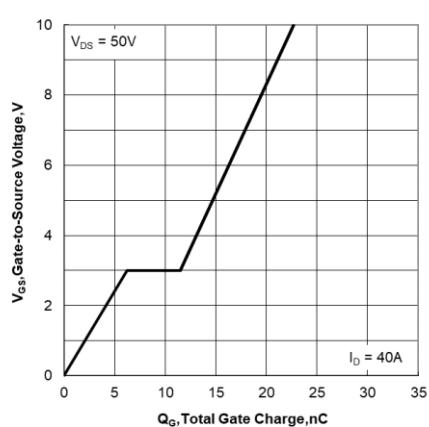
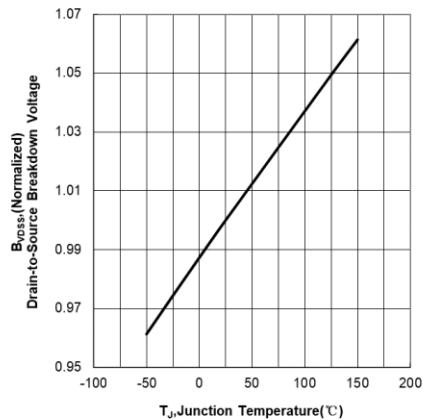


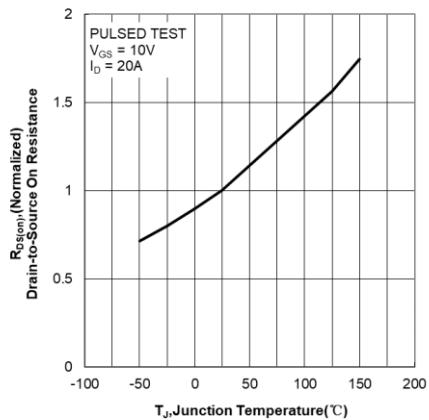
Figure 6. Gate Charge Characteristics

TMG50N10AD

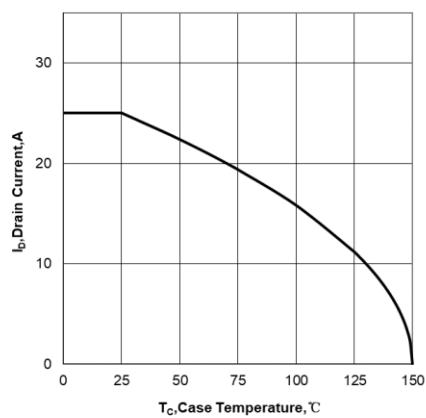
N-Channel Enhancement Mosfet



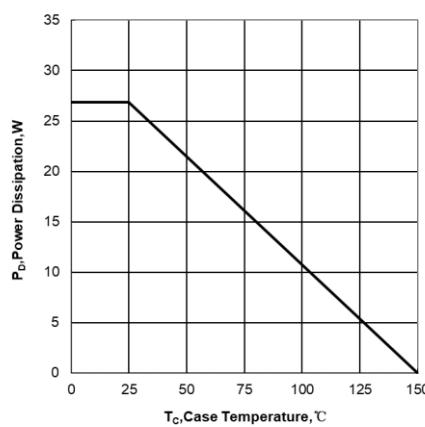
**Figure 7. Normalized Breakdown Voltage
vs Junction Temperature**



**Figure 8. Normalized On Resistance vs
Junction Temperature**



**Figure 9. Maximum Continuous Drain Current
vs Case Temperature**



**Figure 10. Maximum Power Dissipation
vs Case Temperature**

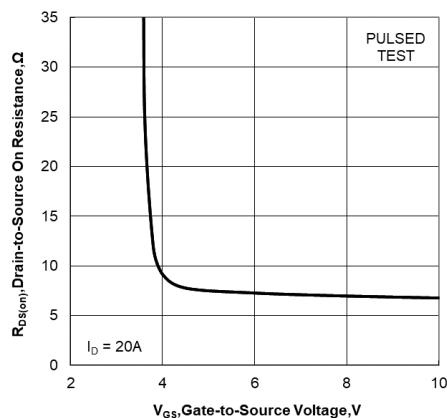


Figure 11. Drain-to-Source On Resistance vs Gate

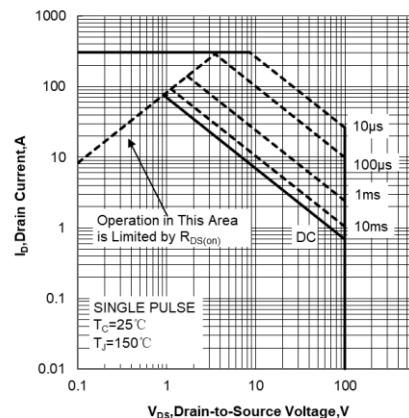


Figure 12. Maximum Safe Operating Area

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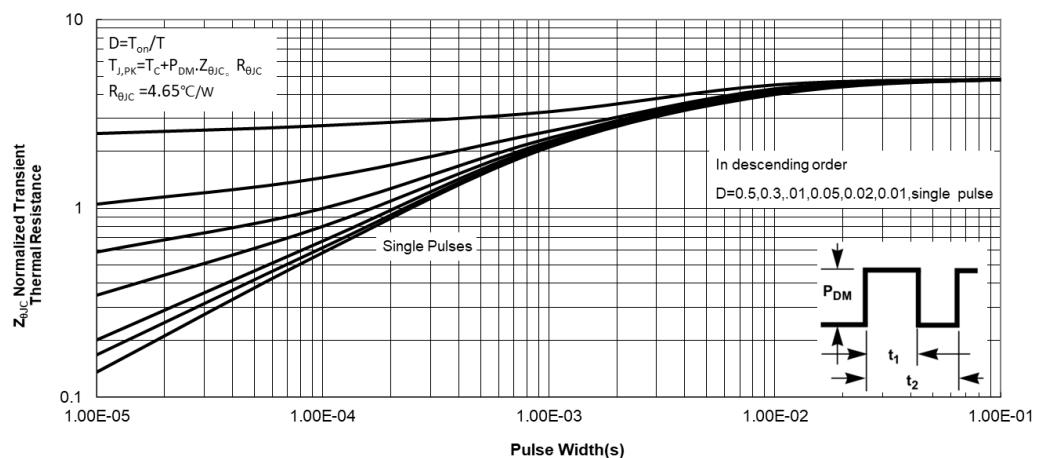
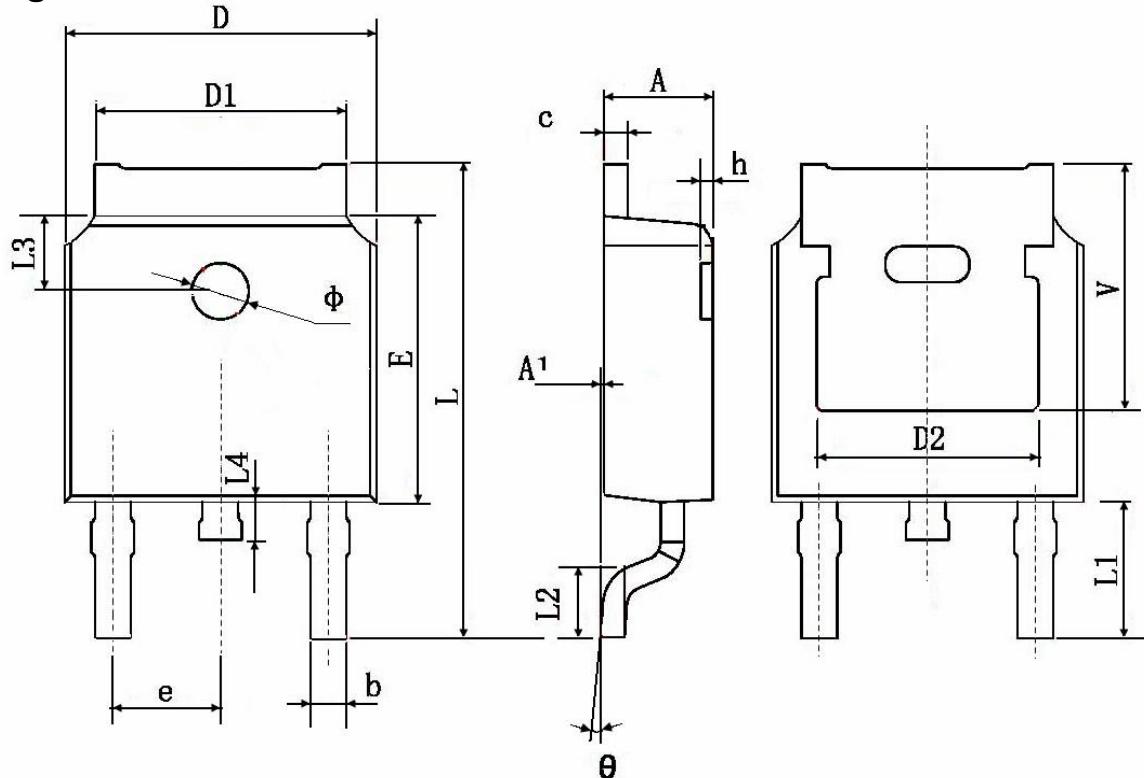


Figure 13. Maximum Effective Transient Thermal Impedance, Junction-to-Case

Package Information: TO-252-3L



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	2.200	2.400	0.087	0.094
A1	0.000	0.127	0.000	0.005
b	0.660	0.860	0.026	0.034
c	0.460	0.580	0.018	0.023
D	6.500	6.700	0.256	0.264
D1	5.100	5.460	0.201	0.215
D2	4.830 TYP.		0.190 TYP.	
E	6.000	6.200	0.236	0.244
e	2.186	2.386	0.086	0.094
L	9.800	10.400	0.386	0.409
L1	2.900 TYP.		0.114 TYP.	
L2	1.400	1.700	0.055	0.067
L3	1.600 TYP.		0.063 TYP.	
L4	0.600	1.000	0.024	0.039
Φ	1.100	1.300	0.043	0.051
θ	0°	8°	0°	8°
h	0.000	0.300	0.000	0.012
V	5.350 TYP.		0.211 TYP.	